Search Notes

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Applicant(s)/Patent under Reexamination

10/006,051

KEATING ET AL.

Art Unit

Examiner

2624

Anand Bhatnagar

	SEAR	CHED	
Class	Subclass	Date	Examiner
382	100,232	7/20/2006	АВ
713	176	7/20/2006	AB
Text	see sheet	7/20/2006	AB
updated	see sheet	7/20/2006	АВ

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
	7/21/2006	АВ	
		Subclass Date	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
382/100,232;380/210,252,287,54;713/ 176;704/200.1,273;381/73.1;348/460, 463 w/text	7/20/2006	АВ
INVENTOR	7/20/2006	AB
IEEE	7/20/2006	AB
(imag\$4 and (DWT wavelet) and (vertical\$4 and horizontal\$4) and (((read\$4 or scan\$6) with (direction\$4 or path\$4))same	7/21/2006	АВ
(imag\$4 and (DWT wavelet) and (LH and HL) and (((read\$4 or scan\$6) with (direction\$4 or path\$4))same (watermark\$4 embed\$4))).	7/21/2006	АВ